(54) **A semiconductor materials inspection system**

Halbleitermaterial-Prüfsystem

Systèmes d'inspection de matériaux à semi-conducteur

(72) Inventors:
• **Owen, Mark D.**
Beaverton, OR 97006 (US)
• **McNeil, Tom**
Portland, OR 97229-1972 (US)
• **Vlach, François**
Beaverton, OR 97006 (US)

(74) Representative: **Murgitroyd, George Edward**
Murgitroyd & Company
Scotland House
165-169 Scotland Street
Glasgow G5 8PL (GB)

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